

SRI LANKA STANDARD 1544 PART 1: 2021
(IEC 61215-1:2021)
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**SPECIFICATION FOR
TERRESTRIAL PHOTOVOLTAIC (PV)
MODULES – DESIGN QUALIFICATION
AND TYPE APPROVAL
PART 1: TEST REQUIREMENTS**
(First Revision)

SRI LANKA STANDARDS INSTITUTION

Sri Lanka Standard
SPECIFICATION FOR TERRESTRIAL PHOTOVOLTAIC (PV) MODULES – DESIGN
QUALIFICATION AND TYPE APPROVAL
PART 1: TEST REQUIREMENTS
(First Revision)

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No. 17, Victoria Place,
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Sri Lanka Standard
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NATIONAL FOREWORD

This standard was approved by the Sectoral Committee on Electronic Engineering and was authorized for adoption and publication as a Sri Lanka Standard by the Council of Sri Lanka Standards Institution on 2021-12-22.

SLS 1544 Sri Lanka Standard Specification for Terrestrial photovoltaic (PV) modules – design qualification and type approval is published in three parts as follows:

- Part 1 : Test requirements
- Part 1-1 : Special requirements for testing of crystalline silicon photovoltaic (PV) modules
- Part 2 : Test procedure

This part of standard is identical with IEC 61215 Terrestrial photovoltaic (PV) modules – design qualification and type approval, Part 1: 2021 Edition 2.0 Test requirements, published by the International Electrotechnical Commission (IEC).

TERMINOLOGY AND CONVENTIONS

The text of the International Standard has been accepted as suitable for publication, without any deviation as a Sri Lanka Standard. However, certain terminology and conventions are not identical with those used in Sri Lanka Standards; attention is therefore drawn to the following:

- a) Wherever the words “International Standard” appear referring to this standard they should be interpreted as “Sri Lanka Standard”.
- b) Wherever the page numbers are quoted they are the page numbers of IEC standard.
- c) The comma has been used as a decimal marker. In Sri Lanka Standards it is the current practices to use a full point on the base line as a decimal marker.
- d) Attention is drawn to the possibility that some of the elements of the Sri Lanka Standard may be the subject of patent rights. SLSI shall not be held responsible for identifying any or all such patent rights.



INTERNATIONAL STANDARD

NORME INTERNATIONALE



**Terrestrial photovoltaic (PV) modules – Design qualification and type approval –
Part 1: Test requirements**

**Modules photovoltaïques (PV) pour applications terrestres – Qualification de la
conception et homologation –
Partie 1: Exigences d'essai**

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